Issue Classification

Applicatio	n/Control No.	Applicant(s)/Patent Reexamination	under					
10/790,29	6	PHAN ET AL.						
Examiner	,	Art Unit						
Paul Dinh		2825						

	ISSUE CLASSIFICATION																
ORIGINAL						CROSS REFERENCE(S)											
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	(Assistant Examiner) (Date) /				Paul Dinh 1/11/06					,	Total Claims Allowed: 30						
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